Search Notes

	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/699,542	LI ET AL.	
Ì	Examiner	Art Unit	
ļ	Peter Coughlan	2129	

SEARCHED					
Class	Subclass	Date	Examiner		
706	45	8/31/2006	PDC		
702	7	8/31/2006	PDC		
707	102	8/31/2006	PDC		
701	50	8/31/2006	PDC		
705	7	8/31/2006	PDC		
702	22	8/31/2006	PDC		
424	122	8/31/2006	PDC		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
East-false positive, false negitive, false identification rates, tester, operating characteristics, processed data	8/31/2006	PDC
EastIIcharactertic curves, alternatives, classifier, cross validation, minimum, minimal, taxomony, model, weight	8/31/2006	PDC
EastIIIsample data, factorial analysis, one way layout	8/31/2006	PDC
IEEEJonathan Qiang Li, Lee A. Barford, one way layout, weight, processed data, factorial analysis, model	8/31/2006	PDC
IEEEIIoperating characteristics, sample data, minimum, minimal, tester, cross validation, identification rates, clasifier	8/31/2006	PDC
IEEEIIIalternatives, charactertic curve, false positive, false negitive	8/31/2006	PDC
Inventors Jonathan Qiang Li Lee A. Barford	8/31/2006	PDC
702/22 with fiting w/model, training set, math expression, weight,	8/31/2006	PDC